

<b>Notice of References Cited</b>	Application/Control No. 10/801,433	Applicant(s)/Patent Under Reexamination YEH ET AL.	
	Examiner Jeanne A. Di Grazio	Art Unit 2871	Page 1 of 1

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*	B	US-6,469,758	10-2002	Yu, Jun Young	349/106
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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